

Customer Information Notification

202304017 | : Update Testflow information for Token in PPAP documentation

Note: This notice is NXP Company Proprietary.

Issue Date: Apr 24, 2023 Effective date: May 21, 2023

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Management summary

This Information Note informs about an update of the documentation of the production test flow for the Token product family. The final test will be carried out at 25C instead of 85C. The three temperature test will be maintained.

Change Category

[]Wafer Fab Process	[]Assembly Process	[]Product Marking	[]Test Process	[]Design
[]Wafer Fab Materials	[]Assembly Materials	[]Mechanical Specification	[]Test Equipment	[]Errata
[]Wafer Fab Location	[]Assembly Location	[]Packing/Shipping/Labeling	[]Test Location	[]Electrical spec./Test coverage
[]Firmware	[X]Other: Documentation			

PCN Overview

Description

The objective of this information note is to inform about updated test flow documentation for the Token product family.

The final production test for Token product family will be carried out at 25C (room temperature) instead of 85C (hot temperature). The three temperature test will be maintained, as the wafer test process includes minimum and maximum specified temperature corners.

There is no change on the product and the tester platform and test coverage will remain the same. A description of the test flow and its validation is attached to this information note (see 'Attached Files').

Reason

The documentation has been updated to reflect the modified test temperature assignment. To support increasing production volume for the Token family, the test flow is standardized by performing the final production test at room temperature.

Identification of Affected Products

Product identification does not change

Anticipated Impact on Form, Fit, Function, Reliability or Quality

No Impact on form, fit, function, reliability or quality

Data Sheet Revision

No impact to existing datasheet

Disposition of Old Products

No change of product

Additional information

Additional documents: view online

Remarks

The ZVEI DeQuMa is not attached, since none of the items is applicable. This note shall update the documentation only.

Remark: The introduction of the test flow as described will start by end of May 2023. All Token products will be considered step by step; hence the transition of all products will take until Q4/2023.

Contact and Support

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

For specific questions on this notice or the products affected please contact our specialist directly:

Name Rolf Lueneberg

Position Customer Quality Manager PL

SCA

e-mail

address rolf.lueneberg@nxp.com

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NXP Quality Management Team.

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High Tech Campus, 5656 AG Eindhoven, The Netherlands

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